EFFECT OF ION IMPLANTATION IN LIQUID PHASE EPITAXIALLY (LPE)-GROWTH EULA GA: YTTRIUM IRON GARNET (YIG) FILMS

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ABSTRACT

The effect of ion implantation in liquid phase epitaxially grown thin films of composition $Eu_{0.6}Y_{2.4}Ga_yFe_{5+y}O_{12}$ and $Eu_{0.1}La_{0.2}Ga_{1.15}Fe_{3.85}O_{12}$ have been studied. Resonance line widths, ΔH_{11} and ΔH_1 , effective g-factor, g_{eff} and uniaxial anisotropy K_u for the unimplanted and the implanted films have been investigated in the temperature range 85K to Tc (430K). the collapse field at room temperature has also been measured. It was found that there is a general tendency that ΔH_{11} increases while ΔH_1 decreases in the ion implanted film. It was also observed that uniaxial anisotropy (K_u) of the implanted film is lower than that of the unimplanted film at all temperature. It was observed, that there is smaller scatter ion the collapse with field for implanted film.

Keywords: technological, unpredictable, ion-implanted, bubble and Hard hubbies

1.0 INTRODUCTION

The rare earth gallium substituted garnet films exhibit interesting physical and magnetic properties which are of fundamental and teleological importance. In the application of magnetic bubble materials for memory device the main obstacle arises from the presence of hard bubbles. Hard hubbies have different spin structure in the domain wall compared to the normal bubbles [W.L. Tabor et.al (1972) and A. P, Molozenoff (1972)] .consequently their response to the rotating in the plane field, which is invariably required for the movement of the bubble from one location to another, is unpredictable. It has been found that ion implantation suppresses the hard bubbles[R. Wolfe et.al (1973)and R. Wolfe and J.C. North, (1972)] and thus provide a very useful technique to the bubble device engineer to improve the performance of the bubble memory device.

Several magnetic and structural studies on ion-implanted garnet films are reported in the literature [V. V. Nemoshkalenko et.al (1990) and H. A. Aigra and J. M. Robertson, (1980)]. We have studied the effect of ion-implantation of composition Eu_{0.6} Y_{2.4}Ga _y Fe _{5+y}O₁₂ (y= 0.9,1) and Eu_{0.1}La_{0.2}Ga_{1.15} Fe _{3.85}O₁₂

2.0 EXPERIMENTAL DETAILS

The garnet films of composition $Eu_{0.6}Y_{2.4}Ga_yFe$ $_{5+y}O_{12}$ (y= 0.9,1) and $Eu_{0.1}La_{0.2}Ga_{1.15}Fe$ $_{3.85}O_{12}$

Was grown on [111]-oriented gadolinium gallium garnet(GGG) substrates using the liquid-phase epitaxy(LPE) technique from PbO-B2O3 base flux. The films have been implanted with Ar' ions at an energy of 80keV and dosage of 10⁴ ions cm⁻² at Tata Institute of Fundamental Research, Mumbai. The implanted depth was estimated to be nearly 2000Å. The thickness of the film was determined using the grooving technique[S. Rosenbaurn(1968) and Maheshwar et.al (1986)], the lattice mismatch, Δa, is obtained from XRD. The magnetization has been obtained using a Faraday balance (George Associates). FMR measurements have been made at 9.08GHz using a Varian E112 spectrometer. The geff has been obtained using the relation:

$$\omega = \gamma_{\text{eff}} \left\{ \left[H_{11} (1.25 H_{11} + H_1) \right]^{\frac{1}{2}} - \left(\frac{H_{11}}{2} \right) \right\}. \tag{1}$$

Where H11 and H1 are the resonance fields for the field parallel and perpendicular to the plane of the film and γ is the gyromagnetic ratio.

The uniaxial Hu was obtained using:

$$H_{u} = 4\pi M_{s} + \{ [H_{11}(1.25H_{11} + H_{1})]^{\frac{1}{2}} - \left(\frac{H_{11}}{2}\right) - H_{1} \}$$
(2)

The uniaxial anisotropy constant K_u was also obtained using

$$K_{u} = \frac{H_{u}M_{s}}{2}.$$

Bubble collapse field has been obtained by observing the bubble domain diameter as a function of applied magnetic field and noting the field at which the bubble domain collapses. Bubble domain have been observed in Reicert Jung Polyvar-Met polarizing microscope. The measured values of the various parameters EuYGaIG and EuLaYGaIG films at room temperature are given in table 1,2,3 &4.

3.0 RESULTS AND DISCUSSION

3.1 Uniaxial anisoiropy (Ku) and geff

The uniaxial anisotropy obtain using eqn. (2) &(3) for unimplanted & implanted films at 300K is listed in table 2.

Table 1 Thickness, lattice mismatch and magnetization measured at 300K for some EuYGaIG and EuLaYGaIG films.

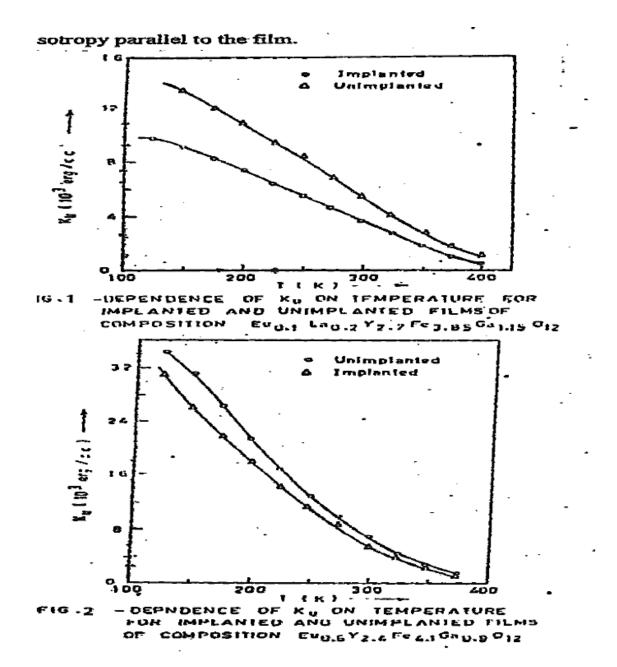
| Composition | Thickness h(µm) | Lattice mismatch Δa(Å) | 4πM _s (G) | |
|--|--------------------|---------------------------|-------------------------|--|
| Eu _{0.6} Y _{2.4} Ga _{0.9} Fe _{4.1} O ₁₂ | 4.93 | 0.034 | 215 | |
| $Eu_{0.6}Y_{2.4}Ga_1Fe_4O_{12}$ | 7.79 | 0.034 | 205 | |
| $Eu_{0.1}La_{0.2}Y_{2.7}Ga_{1.15}Fe_{3.85}O_{12}$ | , 3.60 | 0.020 | 194 | |

Table2 Uniaxial anisotropy (K_u) and g_{eff} of unimplanted and implanted EuYGaIG and EuLaYGaIG films measured at 300K.

| Composition | Unimplan K _u (10 ³ e | nted film rg/cc)g _{eff} | Implant K _u (10 ³ e | ed film erg/cc)g _{eff} | |
|--|---|-------------------------------------|--|------------------------------------|--|
| Eu _{0.6} Y _{2.4} Ga _{0.9} Fe _{4.1} O ₁₂ | 6.9 | 1.47 | 5.6 | 1.48 | |
| $Eu_{0.6}Y_{2.4}Ga_1Fe_4O_{12}$ | 8.9 | 1.38 | 7.2 | 1.37 | |
| Eu _{0.1} La _{0.2} Y _{2.7} Ga _{1.15} Fe _{3.85} O ₁₂ , | 5.4 | 1.96 | 3.7 | 1.96 | |

Since the implanted layer is only about 2000Å thick, the observed anisotropy through ESR is dominated by the growth induce uniaxial anisotropy of the film. It has been observed that the uniaxial anisotropy of the implanted film is always smaller than that of the unimplanted film. It was also observed

that the uniaxial anisotropy of implanted film is lower than that of the unimplanted film at all temperatures as shown in figures.1 to 2. Thus ion implantation suppresses the growth-induced uniaxial anisotropy perpendicular to the film by introducing a stress - induced anisotropy parallel to the film.



The values of geff of implanted film do not differ much from those of unimplanted film. Since there is no compositional modification due to the implantation process, g values do not change, as observed in table 2.

3.2 FMR line width

We have measured the ΔH_{11} and ΔH_{1} of the implanted and unimplanted films. The values of ΔH_{11} and ΔH_{1} at room temperatures are listed in table 3.

Table 3 FMR line width, H11 and H1 for unimplanted and implanted EuYGaIG and EuLaYGaIG films measured at 300K.

| Composition | - | lanted film e) ΔH ₁ (Oe) | | nted film e) ∆H ₁ (Oe) | |
|--|-----|--|-----|--------------------------------------|--|
| Eu _{0.6} Y _{2.4} Ga _{0.9} Fe _{4.1} O ₁₂ | 130 | 380 | 140 | 200 | |
| $Eu_{0.6}Y_{2.4}Ga_1Fe_4O_{12}$ | 200 | 260 | 220 | 320 | |
| Eu _{0.1} La _{0.2} Y _{2.7} Ga _{1.15} Fe _{3.85} O ₁₂ , | 35 | 90 | 50 | 30 | |

It was observed that there is a general tendency that ΔH_{11} increases while ΔH_1 decreases in the ion implanted film.

3.3 Collapse field.

We have measured collapse field for implanted and unirnplanted films, the value of which are given in table 4

Table 4 Values of collapse field of unimplanted and implanted EuYGaIG and EuLaYGaIG films measured at 300K.

| Composition | Unimplanted film Collapse field(Oe) | Implanted film Collapse field(Oe) | |
|--|--|--------------------------------------|--|
| Eu _{0.6} Y _{2.4} Ga _{0.9} Fe _{4.1} O ₁₂ | 45-60 | 45±5 | |
| $Eu_{0.6}Y_{2.4}Ga_1Fe_4O_{12}$ | 62-82 | 65±5 | |
| $Eu_{0.1}La_{0.2}Y_{2.7}Ga_{1.15}Fe_{3.85}O_{12},$ | 75-100 | 75±5 | |

It is observed that there is a smaller scatter in the collapse field which indicates that the hard bubbles have been suppressed by ion implantation

4.0 CONCLUSION

The effect of ion implantation on LPE - grown thin films of composition $Eu_{0.6}Y_{2.4}Ga_vFe_{5-v}O_{12}$.

(y = 0.9, 1) and Eu_{0.1}La_{0.2}Ga_{1.15}Fe_{3.85}O₁₂,have been studied. We have measured the resonance line

widths ΔH_{11} , ΔH_{1} , g_{eff} and K_{u} for the unimplanted and implanted films in the temperature range 85 K to Tc (430 K). We have also measured the collapse field for the unimplanted and implanted films at 3 00K. It was found that ion implantation suppresses the K perpendicular to the film by introducing a stress - induced anisotropy parallel to the film. It has been observed that uniaxial anisotropy of the implanted film is always smaller than that of the unimplanted film. It also observed that uniaxial anisotropy of the implanted film is lower than that of the unimplanted film at all temperature. It is observed that the smaller scatter in the collapse field for implanted film, which indicates that the hard bubbles have been suppressed by ion implantation.

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